

**Search Notes**

Application/Control No.

10/725,132

Examiner

Len Tran

Applicant(s)/Patent under  
Reexamination

ONISHI

Art Unit

1725

**SEARCHED**

Class	Subclass	Date	Examiner
219	109	3/6/2005	LT
	86.9		
	56.22		
	56.21		
	56.1		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST and Palm	3/6/2005	LT